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| <b>Form PTO-1449</b><br>(Rev. 8-83)                                                         | <b>U.S. Department of Commerce</b><br><b>Patent and Trademark Office</b> | <b>Docket No. 740756-2406</b> | <b>Serial No. Not Yet Assigned</b> |
| <b>INFORMATION DISCLOSURE STATEMENT</b><br><small>(Use several sheets if necessary)</small> |                                                                          |                               |                                    |

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|  | <b>Applicant: Shunpei YAMAZAKI et al.</b>               |
|  | <b>Filing Date: January 15, 2002</b> <b>Group: 2813</b> |

**U.S. PATENT DOCUMENTS**

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| <b>Examiner</b> <i>WAL</i> | <b>Date Considered</b> <i>6/28/97</i> |
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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.